

Priorities in Energy Optimized Processing

John Cornish

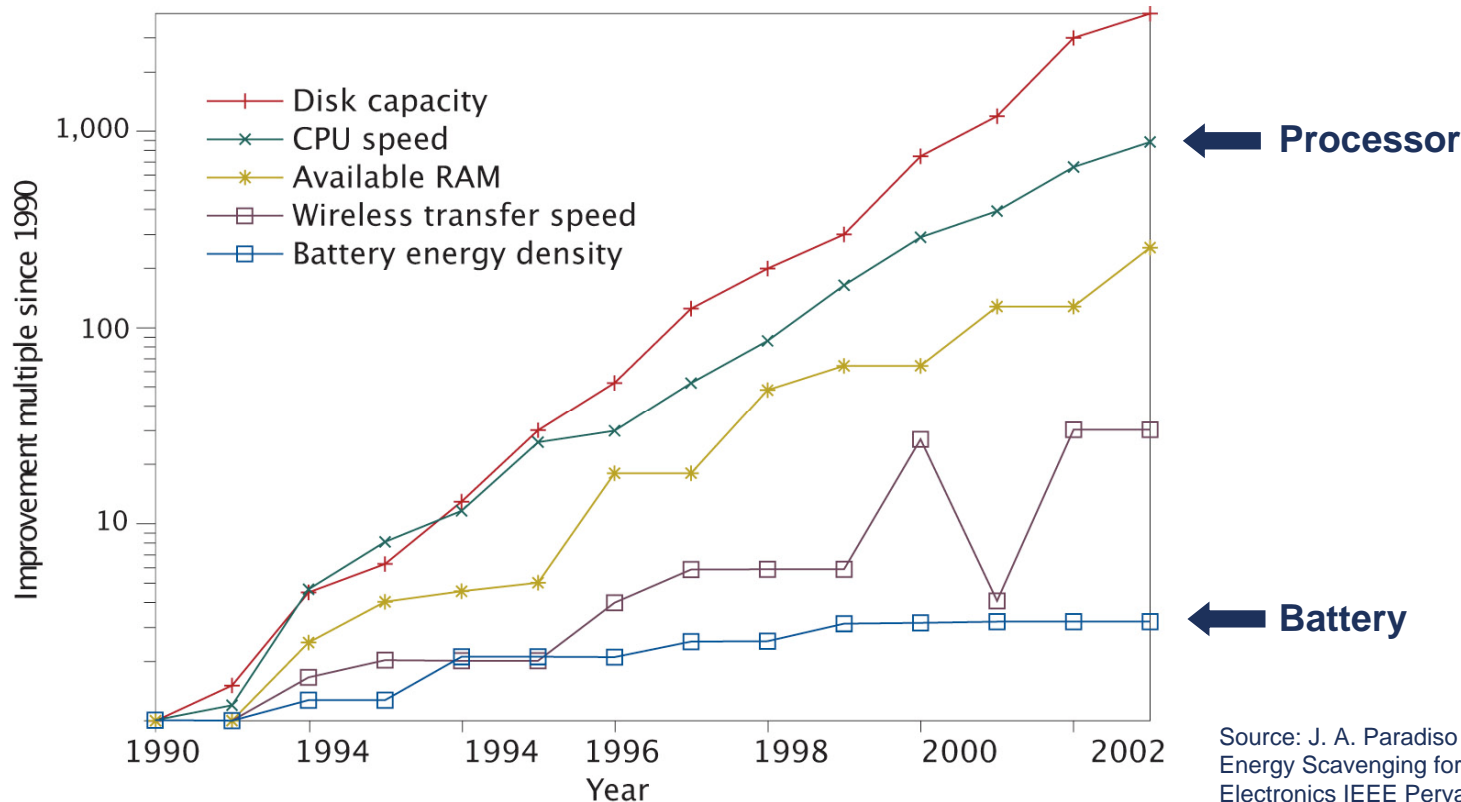
VP Marketing, Processor Division, ARM

11 October, 2006

Constrained Power Footprint

- Everything has improved except the battery!

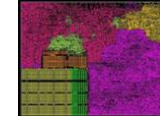
- My phone in 1998: Nokia 6110 270h standby 900mAh NiMH
- My current phone: iMate SP5 250h standby 1150mAh Lithium-ion



Source: J. A. Paradiso and T. Starner, Energy Scavenging for Mobile and Wireless, Electronics IEEE Pervasive Computing, 2005.

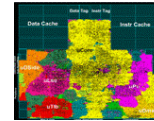
Exploiting Process Technology

Cortex-A8
2000 DMIPS
<300mW



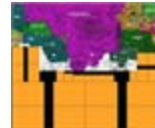
Uncertainty
Variability

ARM11
920 DMIPS
<350mW



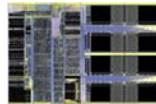
Leakage Power
Lithography

ARM10E
360 DMIPS
<160mW



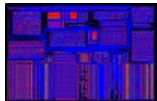
Signal Integrity
CMP

ARM9E
220 DMIPS
<225mW



Timing Closure
Vias

ARM7
60 DMIPS
<50mW



Timing, Area
Particles

250nm

180nm

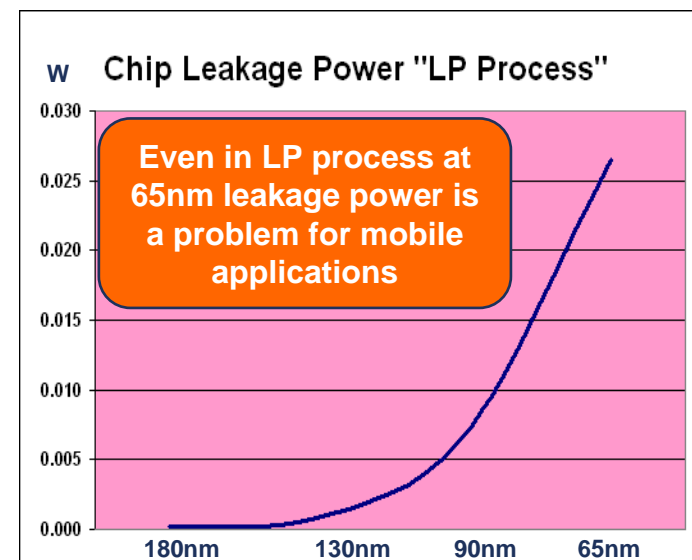
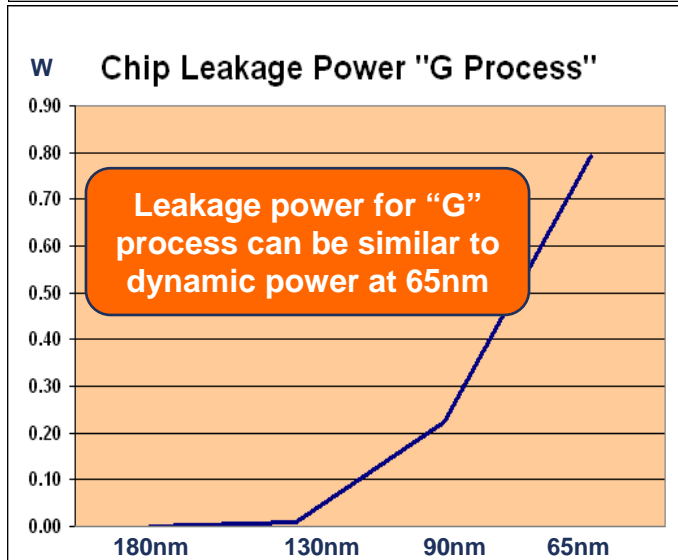
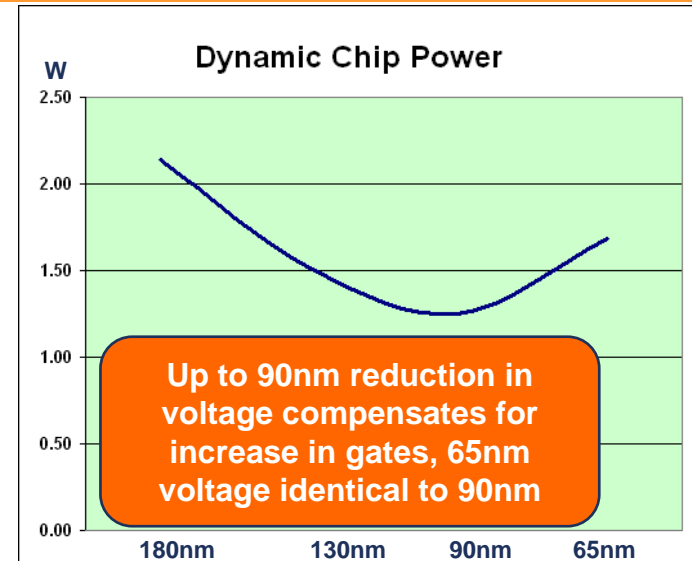
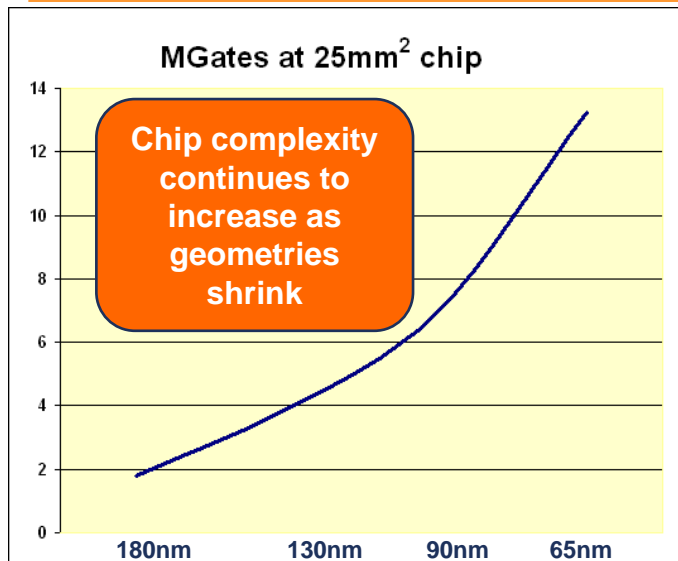
130nm

90nm

65nm

45nm

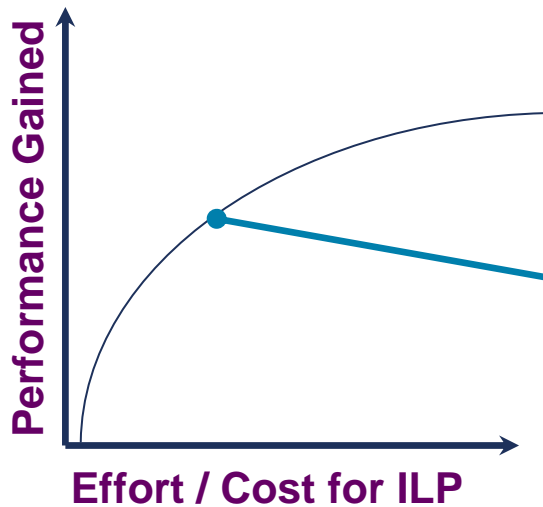
Complexity and Power Explosion



1. Gates per chip based on 75% standard cells and 80% utilization for 25mm² chip per process node,

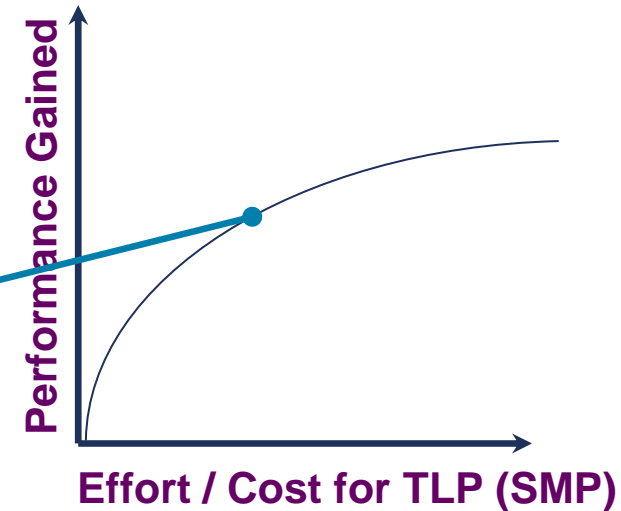
2. Power based on number of gates from 1, dynamic power with 250MHz and 30% activity, leakage power at 125C, FF, VDD+10%

Multiprocessing (MP)



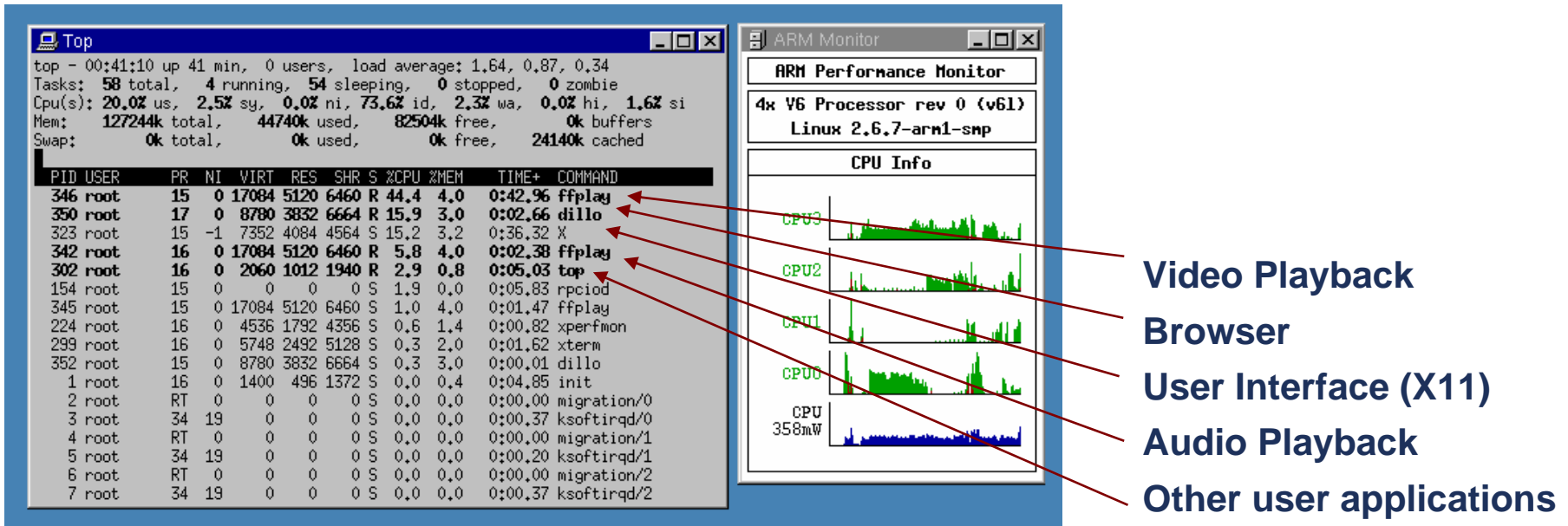
Expensive on hardware to continue to attempt to extract instruction level parallelism (ILP)

'Optimal' support for both ILP and TLP brings the most performance for the least cost / effort



Expensive on hardware and software to continue to attempt to share work between more instances of thread level parallelism (TLP)

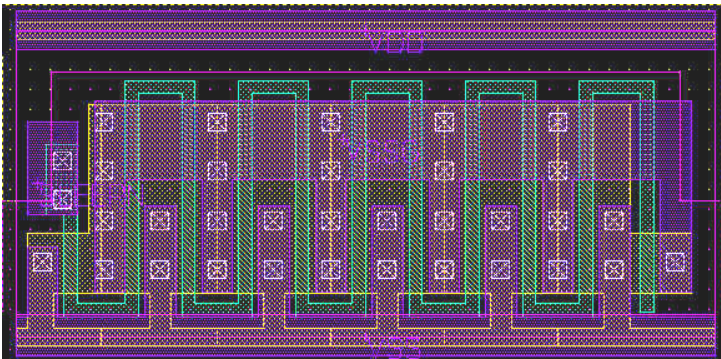
MP – Exploiting Concurrency



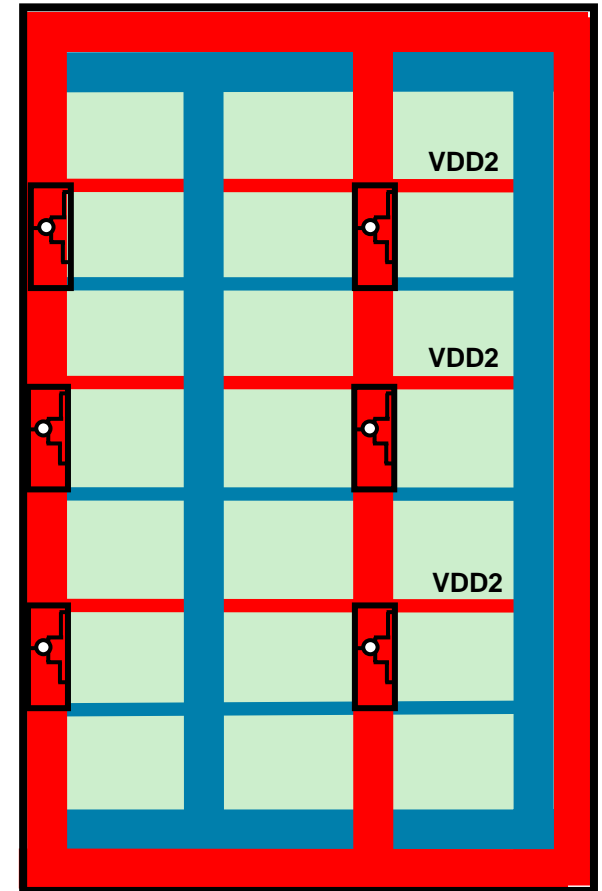
- Multi-tasking
 - Inherent within applications and the operating system
- Multi-threading
 - Offloading tasks to specialist processors
 - Creating a 'pool' of tasks the OS can share across general SMP processor
 - Exposing utility tasks that can be scheduled in the background

Power Gating

- Coarse grain power switches
 - Switching power or ground for multiple cells at block level
 - Disconnect local power from global power via power gates (MTCMOS switches)
- Header and Footer switches allow flexibility
 - Header to switch VDD, Footer to switch VSS
 - Same cell height as normal cells
 - Different transistor sizes (cell width) available

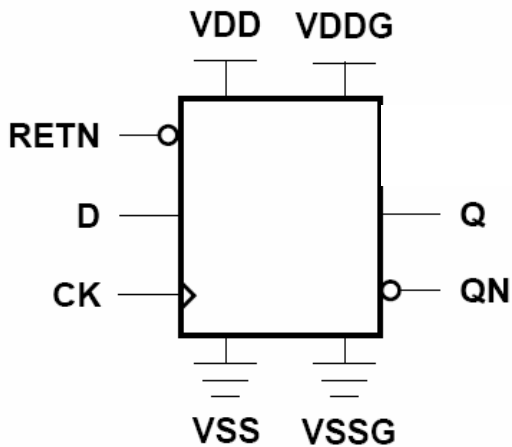
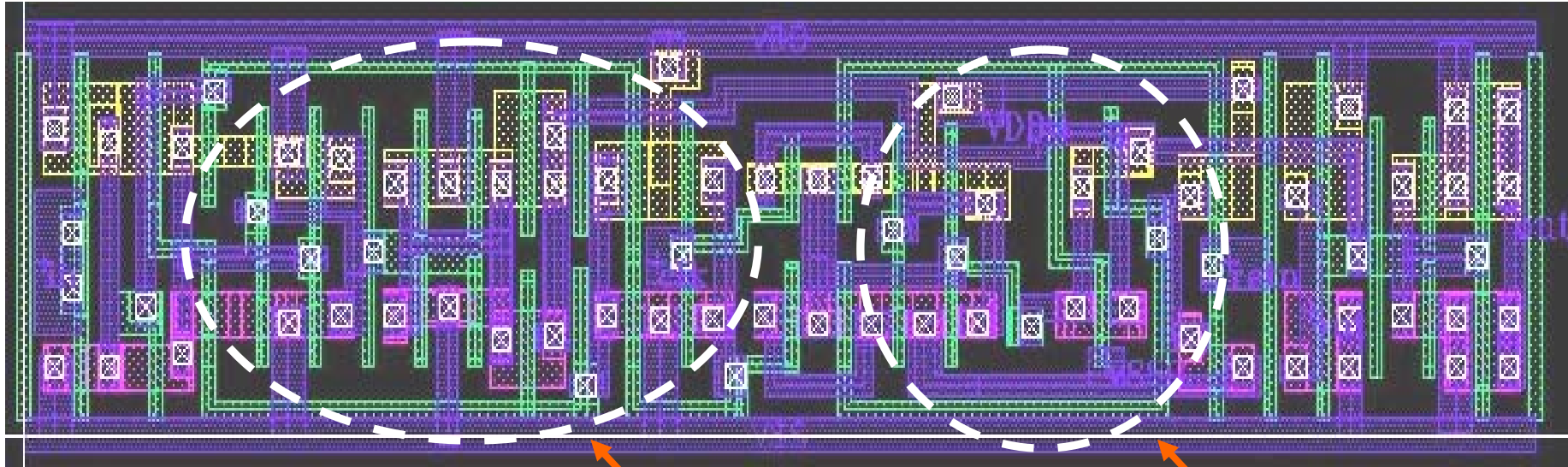


Example Footer Switch



Switches on the connection power strip and power rail to switch VDD2

State Retention



1. D-flop main stage (SVt or LVt)

- No leakage when retaining state
- Connects to switchable (local) power rails

2. D-flop retention stage (HVT)

- Low leakage when retaining state
- Connects to global (always-on) power

65LP Leakage Analysis

- Correlating measurements

- IV analysis for CPU+RAM
RAM requires 1.08V min

- HALT

- Std cell + RAM leakage

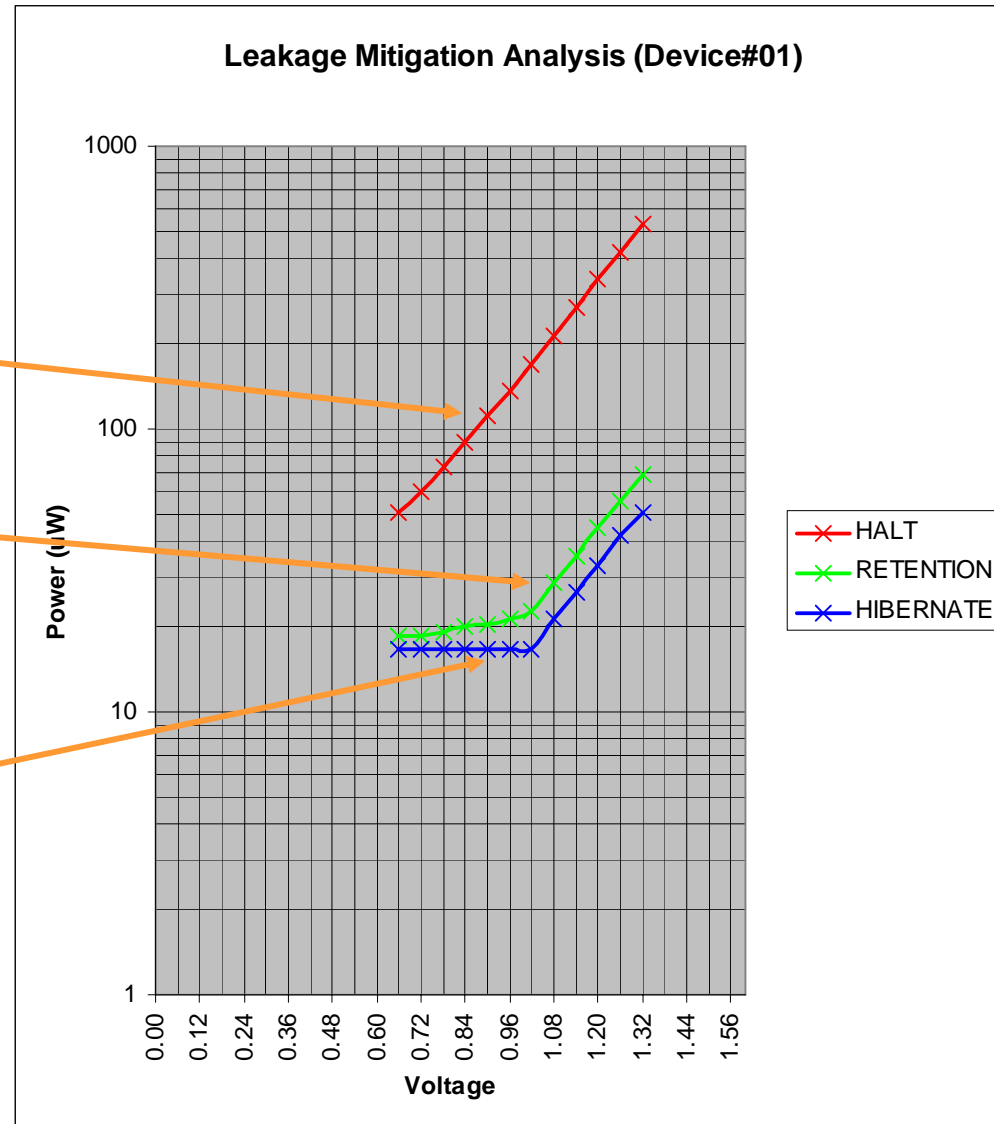
- LIGHT SLEEP

- Lvt Std cell power gated
- Retention registers active
- + RAM leakage

- DEEP SLEEP

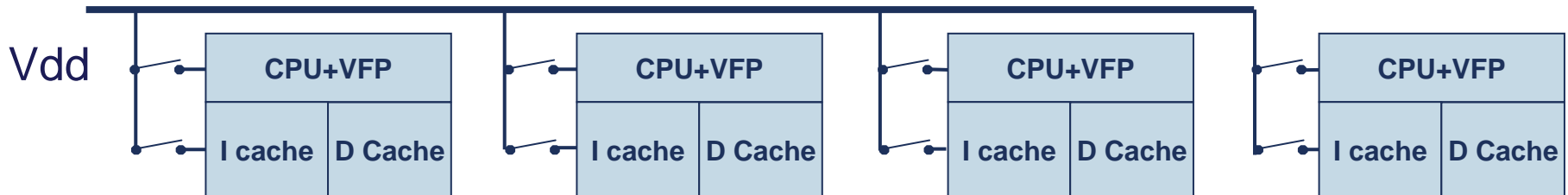
- Scan-based hibernate
- Just RAM leakage

All at room temp (23C)



MP – Exploiting Power Gating

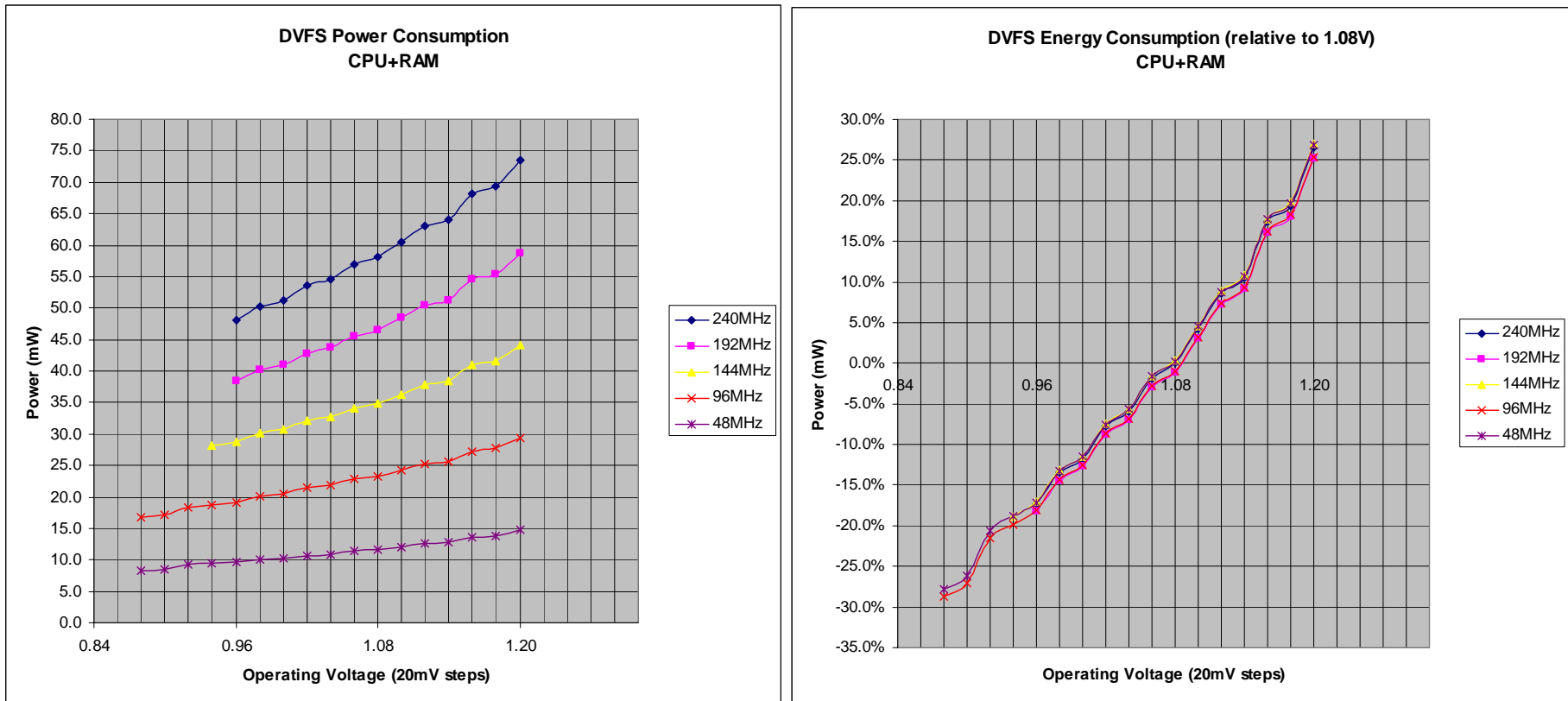
- Enter Standby using wait-for-interrupt
 - Maintain cache coherence while in standby
 - Allows immediate re-entry without any cache house keeping
- Enter Dormant/Shutdown state
 - Remove supply to core logic but maintain RAM
 - Remove supply and save dynamic and leakage power
 - Requires all dirty cache data to be evicted prior to entry
 - Awoken CPU reloads state and rejoins the coherence domain



Dormant – Core logic powered down, cache retains contents

Shutdown – Core logic **and** cache powered down

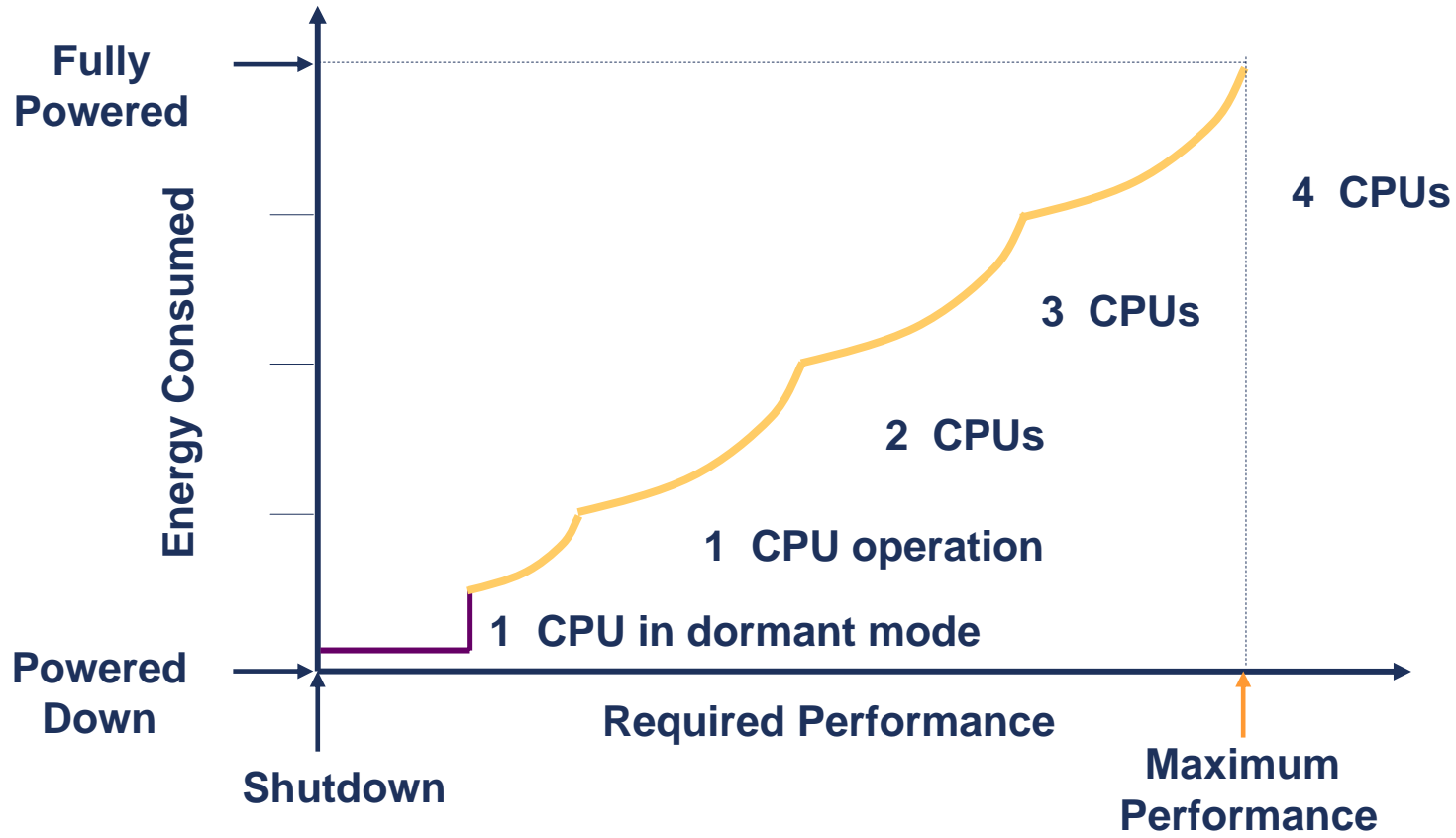
Dynamic Voltage & Frequency Scaling



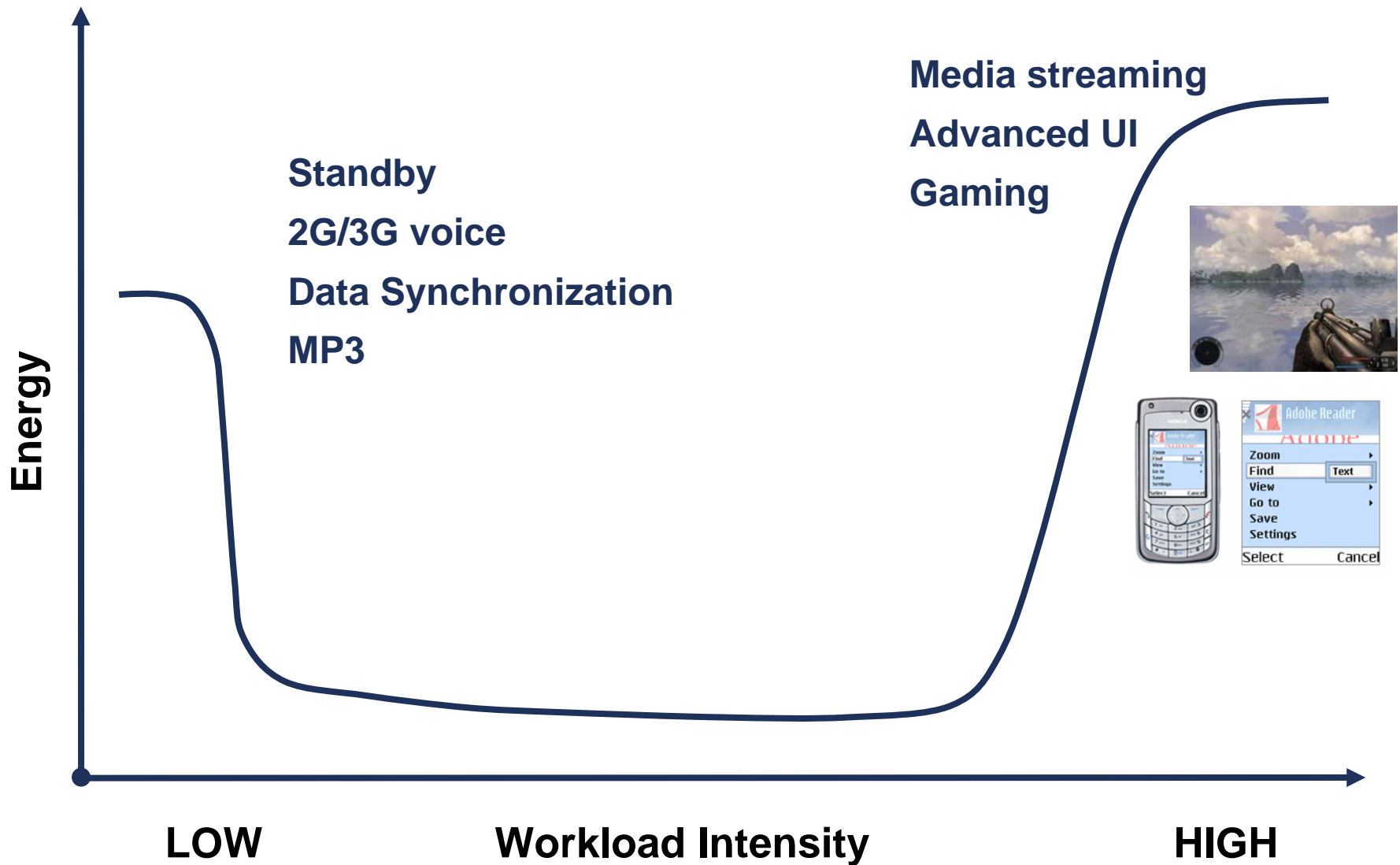
- 65LP process, typical silicon, 23 degC
- RAM not safely scalable below 1.08V
- Over 40% energy savings measurable from 1.2V

MP – Exploiting DVFS

MP extends control over power usage by implementing voltage and frequency scaling and turning off unused processors



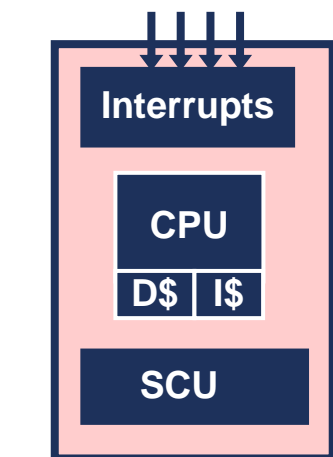
Workload Variance



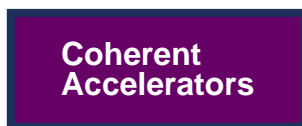
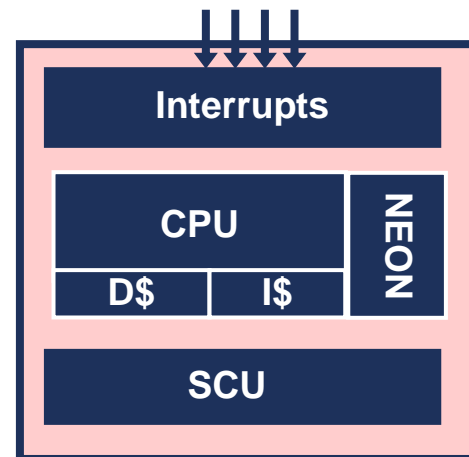
MP – Exploiting Workload Variance

- Enable tasks to migrate between cores with different performance capabilities and power footprints
- Minimise energy consumption using adaptive shutdown

Low Intensity Workloads

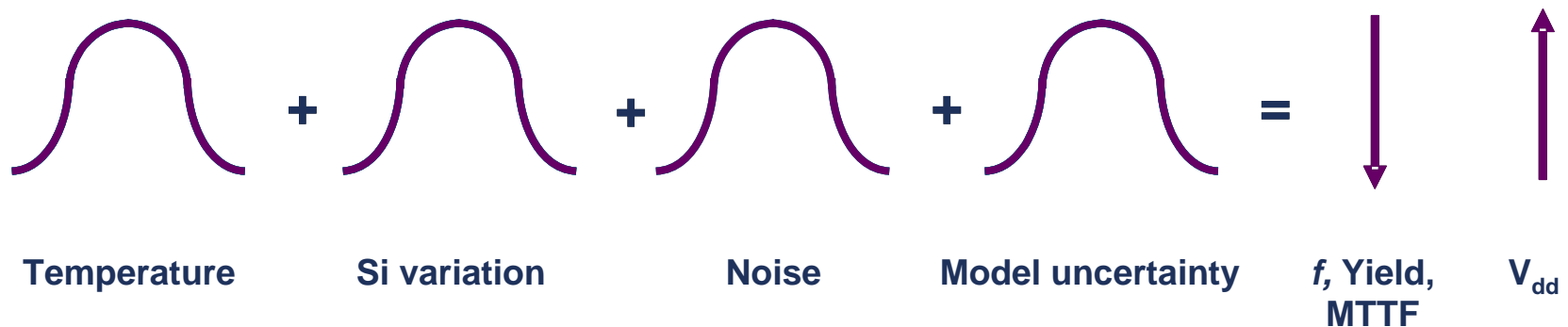


High Intensity Workloads



Exploiting Uncertainty

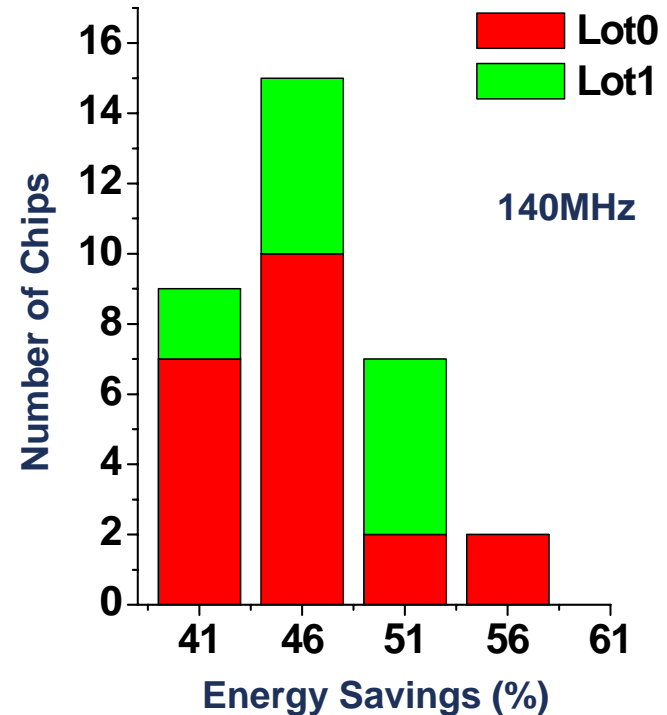
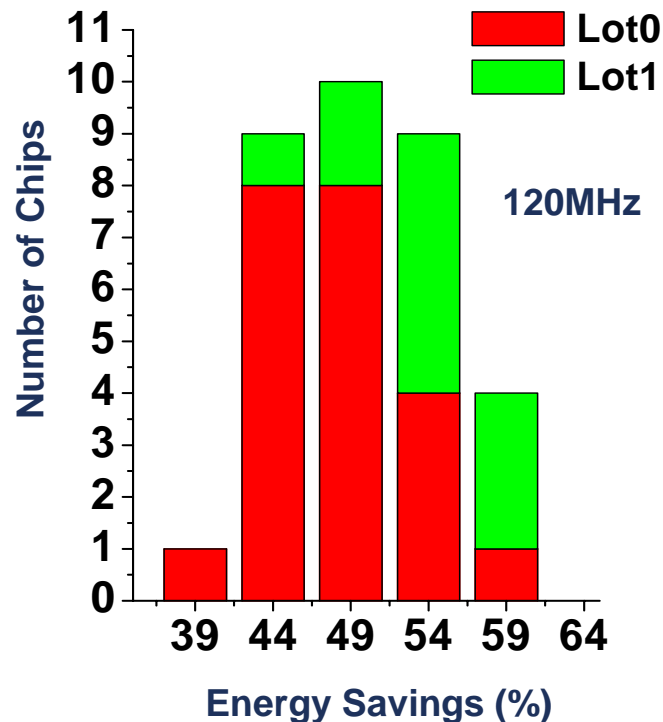
- Uncertainty leads to performance and power overheads
 - Increasing uncertainty with design scaling
 - Intra-die process/temperature variations, inductive noise
- Key Observation: worst-case conditions are highly improbable
 - Significant gain for circuits optimized for common case
 - Need mechanisms to tolerate infrequent worst-case scenarios



Razor – Beyond Worst Case Design

- Deep submicron processes are problematic
 - Process variation, IR-drop, temperature fluctuation, model uncertainty
- Standard solution: larger built-in safety margins
 - Yields lower performance, higher cost, higher power devices
- Most severe problems are also the least frequent
 - Soft errors, capacitive, inductive noise, charge sharing...
 - Only pay a penalty when the problem actually occurs!
- Break some conventions
 - Computation may not always be correct
 - Miss timing some of the time, compensate at run-time
- Speculate on correctness
 - Assume that circuits work as expected, recover if not
 - Speculation is key to minimizing run-time overhead

Energy Savings Using Razor



- Under typical case conditions all chips at least 39% more energy efficient
 - Worst-case design uses margins for corners that are very infrequent
- Typical-case operation requires an understanding of when and how systems break
 - Razor specifies the microarchitectural requirements

Summary

- Energy efficiency is now the limiting factor for many systems
- Industry challenge is to maximise the usable performance from a highly constrained energy envelope
- Market growth requires improved features and lower cost
- Heterogeneous MP clusters offer the potential for large increases in average energy efficiency
- Exploiting uncertainty can reduce energy through elimination of margins and correction of errors